# 3<sup>rd</sup> Generation 650V/30A SiC Schottky Barrier Diode

# Features

- Revolutionary semiconductor material Silicon Carbide (SiC)
- No reverse recovery
- High-speed switching performance
- > Temperature-independent switching behavior
- System cost / size savings due to reduced cooling requirements
- Junction temperature range from -55°C to 175°C
- RoHS compliant

# **Potential Applications**

- Industrial power supplies: Industrial UPS
- Battery chargers
- Solar inverters
- Switch mode power supplies

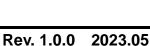
# Description

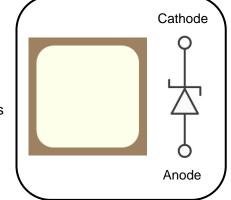
The SDS065J030B3 SiC Schottky Barrier Diode (SBD) has been developed using Sanan's advanced 3<sup>rd</sup> generation SiC SBD technology with the highest performance and reliability. It registers higher efficiency, higher operation temperature and lower loss and can be operated at higher frequency than Si-based solutions. As to the Schottky structure, it shows no recovery at turn-off and allows a low leakage current with reverse voltage up to 650V. It can contribute to system miniaturization and achieve lightweight system design. Using RoHS compliant components, it is qualified for use in industrial application.

# **Product Specifications**

Device	V <sub>RRM</sub>	I <sub>F</sub> (135°C)	V <sub>F</sub> (25°C)	Qc	
SDS065J030B3	650V	38A	1.35V	83nC	

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# Table 1. Maximum Ratings

(Tc = 25°C, unless otherwise specified)
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Parameter	Symbol	Value	Unit	Test conditions
Repetitive peak reverse voltage	V <sub>RRM</sub>	650		T <sub>C</sub> = 25°C
Surge peak reverse voltage	V <sub>RSM</sub>	650	V	T <sub>C</sub> = 25°C
DC reverse voltage	V <sub>DC</sub>	650		T <sub>c</sub> = 25°C
		75		T <sub>c</sub> = 25°C
Continuous forward current	IF	36	А	T <sub>C</sub> = 135℃
		30		T <sub>C</sub> = 155°C
Surge non-repetitive forward current	I <sub>FSM</sub>	214	А	$T_{C} = 25^{\circ}C$ , $t_{p} = 10ms$ , half sine pulse
Repetitive peak forward current	I <sub>FRM</sub>	153	A	$T_{C} = 25^{\circ}C$ , $t_{p} = 10ms$ , half sine wave D = 0.1
i <sup>2</sup> t value	∫i²dt	229	A <sup>2</sup> s	$T_{C} = 25^{\circ}C, t_{p} = 10ms$
Operating junction temperature	Tj	-55~175	°C	
Storage temperature	T <sub>stg</sub>	-55~175	°C	

## Table 2. Thermal Resistance

Deremeter	Symbol	,	Values		Unit	Test
Parameter	Symbol	Min. Typ. M	Max.	condition		
Thermal resistance from junction to case	R <sub>th(j-c)</sub>	/	0.60	/	°C/W	

\*Thermal Resistance is collected in TO247-2L

### Table 3. Static Electrical Characteristics

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Parameter	Symbol Mi	Min.	Тур.	Max.	Unit	Test conditions
DC blocking voltage	V <sub>DC</sub>	650	/	/	V	I <sub>R</sub> = 100 μA
E I IV	VF	/	1.35	1.50	V	$I_F=30A,T_j=25^\circ\!\mathrm{C}$
Forward voltage		/	1.55	2.20		I <sub>F</sub> = 30A, T <sub>j</sub> = 175°C
Reverse current	1-	/	3	90		$V_R = 650V, T_j = 25^{\circ}C$
	I <sub>R</sub>	/	20	180	μA	$V_R = 650V, T_j = 175^{\circ}C$

#### (T<sub>j</sub> = 25°C, unless otherwise specified)

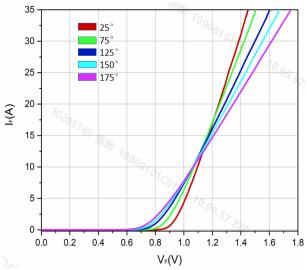
# **Table 4. Dynamic Electrical Characteristics**

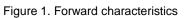
Deservation	0 miles l	Values			11 14	<b>T</b>
Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions
		/	1677	/		$V_R = 0V$ , f = 1MHz
Total capacitance	С	/	157	/	pF	V <sub>R</sub> = 200V, f = 1MHz
		/	131	/		V <sub>R</sub> = 400V, f = 1MHz
Total capacitive charge	Qc	/	83	/	nC	V <sub>R</sub> = 400V
Capacitance stored energy	Ec	/	12	/	μJ	V <sub>R</sub> = 400V



# **Electrical Characteristic Diagrams**

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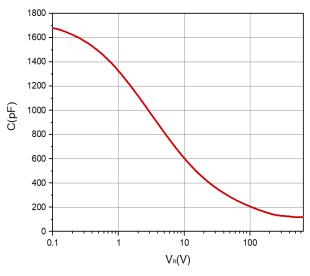


Figure 3. Capacitance vs. reverse voltage

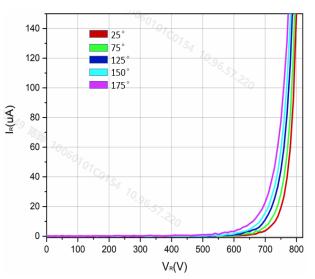


Figure 2. Reverse characteristics

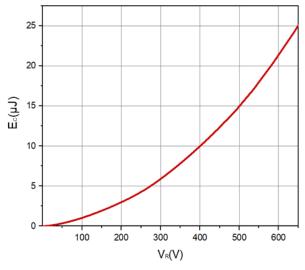


Figure 4. Capacitance stored energy



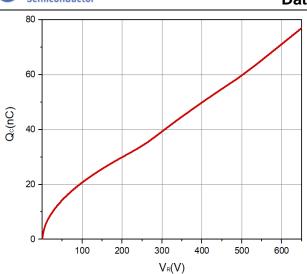


Figure 5. Total capacitance charge vs. reverse voltage

### **Ordering Information**

Part Number	SDS065J030B3
Package	Bare Die
Packing Method	Wafer
RoHS	Yes

# Important Notices – Read Carefully

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#### Datasheet

#### SDS065J030B3

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